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PATENT 7-8-98

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Wayne A. Bonin

Serial No.: 08/965,332 Examiner D. Larkin

Filed: November 6, 1997 Group Art Unit 2605

For: APPARATUS FOR MICROINDENTATION HARDNESS TESTING AND  
SURFACE IMAGING INCORPORATING A MULTI-PLATE  
CAPACITOR SYSTEM

Docket No.: 55463/101/103

Assistant Commissioner for Patents  
Washington, D.C. 20231

Sir:

PRELIMINARY AMENDMENT

In the Claims

Rewrite claim 41 as follows:

K1  
1 ~~41~~. (Amended) In a [A] scanned probe microscope apparatus having a probe and a scanning head operably arranged for measuring surface properties of a sample, the apparatus improvement comprising:

a high precision capacitance sensor having a pick-up plate movably mounted relative to a drive plate;

means for transmitting force between an object remote from the pick-up plate and the pick-up plate; and

means responsive to the position of the pick-up plate relative to the drive plate for providing an output signal proportional to the relative position.